

**Search Notes**

Application/Control No.

10/527,155

Examiner

Mark A. Chapman

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

1756

**SEARCHED**

Class	Subclass	Date	Examiner
430	108.6	6/19/2007	MC
	108.1		
	137.2		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	6/19/2007	MC